Appl. No. 09/803,084 Amdt. Dated August 27, 2003 Reply to Office Action of July 8, 2003

This listing of claims replaces all prior versions, and listings of claims in the instant application:

Listing of Claims:

- 1. (original) A wafer comprising:
- a first surface;
- a second surface;
- a first scribe line coupled to said first surface, said first scribe line extending in a first direction;
- a second scribe line coupled to said first surface, said second scribe line extending in a second direction perpendicular to said first direction; and
- a first alignment mark formed at an intersection of said first scribe line and said second scribe line, said first alignment mark extending from said first surface to said second surface.
- 2. (original) The wafer of Claim 1 further comprising a scribe grid comprising said first scribe line and said second scribe line.
- 3. (original) The wafer of Claim 2 further comprising electronic components delineated by said scribe grid.
- 4. (original) The wafer of Claim 3 wherein said electronic components are selected from the group consisting of integrated circuits, micromachine chips and image sensor chips.
- 5. (original) The wafer of Claim 3 wherein said electronic components comprise bond pads coupled to said first surface.

Amdt. Dated August 27, 2003

Reply to Office Action of July 8, 2003

- 6. (original) The wafer of Claim 3 wherein said electronic components comprise active areas coupled to said first surface.
- 7. (original) The wafer of Claim 1 further comprising a flat extending in said second direction.
- 8. (original) The wafer of Claim 1 wherein said first scribe line delineates a first electronic component from a second electronic component.
- 9. (original) The wafer of Claim 8 wherein said second scribe line delineates said second electronic component from a third electronic component.
- 10. (original) The wafer of Claim 1 wherein said first alignment mark is an aperture.
- 11. (original) The wafer of Claim 1 further comprising a first plurality of alignment marks comprising said first alignment mark, said first plurality of alignment marks extending from said first surface to said second surface.
- 12. (original) The wafer of Claim 11 wherein said first plurality of alignment marks are aligned with said first scribe line.
- 13. (original) The wafer of Claim 12 further comprising a second plurality of alignment marks aligned with a third scribe line coupled to said first surface and extending in said second direction.

Amdt. Dated August 27, 2003

Reply to Office Action of July 8, 2003

- 14. (original) The wafer of Claim 11 wherein said first plurality of alignment marks define a first line, said first line being aligned with said first scribe line.
- 15. (original) The wafer of Claim 14 further comprising a second plurality of alignment marks defining a second line, said second line being aligned with a third scribe line coupled to said first surface and extending in said second direction.

16-22. (canceled)

- 23. (previously presented) A wafer comprising:
- a first surface;
- a second surface;
- a scribe grid coupled to said first surface; and
- a plurality of alignment marks extending from said first surface to said second surface, said plurality of alignment marks having a positional relationship to said scribe grid.
- 24. (original) The wafer of Claim 23 wherein said scribe grid comprises a horizontal scribe line, a first set of said plurality of alignment marks being aligned with said horizontal scribe line.
- 25. (original) The wafer of Claim 24 wherein said scribe grid comprises a vertical scribe line, a second set of said plurality of alignment marks being aligned with said vertical scribe line.

26-29. (canceled)

30. (previously presented) The wafer of Claim 2 wherein said scribe grid comprises an etched silicon oxide layer.

Amdt. Dated August 27, 2003

Reply to Office Action of July 8, 2003

- 31. (previously presented) The wafer of Claim 23 wherein said scribe grid comprises an etched silicon oxide layer.
- 32. (previously presented) The wafer of Claim 23 further comprising electronic components delineated by said scribe grid.
- 33. (previously presented) The wafer of Claim 32 wherein said electronic components are selected from the group consisting of integrated circuits, micromachine chips and image sensor chips.
- 34. (previously presented) The wafer of Claim 32 wherein said electronic components comprise bond pads coupled to said first surface.
- 35. (previously presented) The wafer of Claim 32 wherein said electronic components comprise active areas coupled to said first surface.
- 36. (previously presented) The wafer of Claim 25 wherein said vertical scribe line extends in a first direction and wherein said horizontal scribe line extends in a second direction, said wafer further comprising a flat extending in said second direction.
 - 37. (previously presented) A wafer comprising:
 - a front-side surface:
 - a back-side surface;
- a first scribe line coupled to said front-side surface; and
- a first back-side alignment mark extending from said front-side surface to said back-side surface, said first backside alignment mark being formed along said first scribe line.

Amdt. Dated August 27, 2003

Reply to Office Action of July 8, 2003

- 38. (previously presented) The wafer of Claim 37 further comprising a plurality of back-side alignment marks extending from said front-side surface to said back-side surface, said plurality of back-side alignment marks comprising said first back-side alignment mark.
- 39. (previously presented) The wafer of Claim 38 wherein said plurality of back-side alignment marks have a positional relationship to said first scribe line.
 - 40. (previously presented) A wafer comprising:
 - a first surface;
 - a second surface;
 - a scribe line coupled to said first surface; and
- a means for determining a position of said scribe line from said second surface, said means for determining extending through said wafer from said first surface to said second surface.
- 41. (new) The wafer of Claim 1 wherein said first alignment mark is for aligning a saw with said wafer.